

# SSU60R2K3S-VB Datasheet N-Channel 600V (D-S) Super Junction Power MOSFET

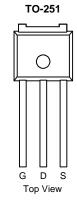
PRODUCT SUMMARY				
V <sub>DS</sub> (V)	600			
$R_{DS(on)}\left(\Omega\right)$	V <sub>GS</sub> = 10 V	2.3		
Q <sub>g</sub> (Max.) (nC)	31			
Q <sub>gs</sub> (nC)	4.6			
Q <sub>gd</sub> (nC)	17			
Configuration	Single			

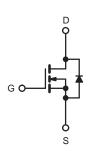
#### **FEATURES**

- · Isolated Package
- High Voltage Isolation = 2.5 kV<sub>RMS</sub> (t = 60 s;



- Sink to Lead Creepage Distance = 4.8 mm
- · Dynamic dV/dt Rating
- · Low Thermal Resistance
- Lead (Pb)-free Available





N-Channel MOSFET

PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			$V_{DS}$	600	.,	
Gate-Source Voltage			$V_{GS}$	± 20	V	
Continuous Drain Current	V <sub>GS</sub> at 10 V	$T_{\rm C} = 25 ^{\circ}{\rm C}$ $T_{\rm C} = 100 ^{\circ}{\rm C}$	,	2.0		
	VGS at 10 V	T <sub>C</sub> = 100 °C	ID	1.6	Α	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	10	1	
Linear Derating Factor				0.28	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	250	mJ	
Repetitive Avalanche Current <sup>a</sup>			I <sub>AR</sub>	2.5	А	
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	3.5	mJ	
ximum Power Dissipation T <sub>C</sub> = 25 °C			P <sub>D</sub>	35	W	
Peak Diode Recovery dV/dtc			dV/dt	3.0	V/ns	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for	10 s	,	300 <sup>d</sup>	7	
Manada Tanana	6-32 or M3 screw			10	lbf ⋅ in	
Mounting Torque				1.1	N⋅m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b.  $V_{DD}$  = 50 V, starting  $T_J$  = 25 °C, L = 73 mH,  $R_G$  = 25  $\Omega$ ,  $I_{AS}$  = 1.5 A (see fig. 12).
- c.  $I_{SD} \le 1.6$  A,  $dI/dt \le 60$  A/ $\mu$ s,  $V_{DD} \le V_{DS}$ ,  $T_J \le 150$  °C.
- d. 1.6 mm from case.

<sup>\*</sup> Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	65	°C/W	
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	3.6	C/VV	

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		600	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	Reference to 25 °C, I <sub>D</sub> = 1 mA		0.62	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		-	4.0	V
Gate-Source Leakage	I <sub>GSS</sub>		V <sub>GS</sub> = ± 20 V		-	± 100	nA
Zoro Coto Voltogo Droin Current		V <sub>DS</sub> =	V <sub>DS</sub> = 600 V, V <sub>GS</sub> = 0 V		-	100	μΑ
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 480 \	V <sub>DS</sub> = 480 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C		-	500	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 1.5 A <sup>b</sup>	-	2.3	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> =	= 50 V, I <sub>D</sub> = 1.5 A <sup>b</sup>	2.2	-	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>		V <sub>GS</sub> = 0 V,		660	-	
Output Capacitance	C <sub>oss</sub>	]	$V_{DS} = 25 V$ ,	-	86	-	1 _
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1	f = 1.0 MHz, see fig. 5		19	-	pF
Drain to Sink Capacitance	С		f = 1.0 MHz	-	12	-	
Total Gate Charge	Qg			-	-	31	
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V	$I_D = 1.6 \text{ A}, V_{DS} = 360 \text{ V},$ see fig. 6 and $13^b$	-	-	4.6	nC
Gate-Drain Charge	Q <sub>gd</sub>	1	See fig. 6 and 16	-	-	17	
Turn-On Delay Time	t <sub>d(on)</sub>			-	11	-	
Rise Time	t <sub>r</sub>	V <sub>DD</sub> =	: 300 V, I <sub>D</sub> = 1.6 A,	-	13	-	]
Turn-Off Delay Time	t <sub>d(off)</sub>	$R_G = 12 \Omega, R_D = 82 \Omega,$ see fig. $10^b$		-	35	-	ns ns
Fall Time	t <sub>f</sub>			-	14	-	
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	-11
Internal Source Inductance	L <sub>S</sub>			-	7.5	-	- nH
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	2.0	А
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	10	A
Body Diode Voltage	$V_{SD}$	T <sub>J</sub> = 25 °C	$I_{S} = 1.5 \text{ A}, V_{GS} = 0 \text{ V}^{b}$	-	-	1.6	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	T. = 25 °C 1	T 05 00 1 4 0 4 31/4 400 4 / b		400	810	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	$T_J = 25 ^{\circ}\text{C}, I_F = 1.6 \text{A}, dI/dt = 100 \text{A/}\mu\text{s}^b$			2.1	4.2	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic to	on is don	on is dominated by L <sub>S</sub> and L <sub>D</sub> )			

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width  $\leq$  300 µs; duty cycle  $\leq$  2 %.



#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

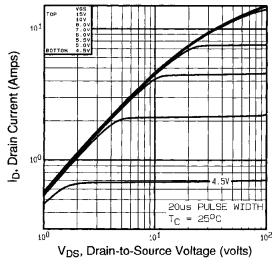


Fig. 1 - Typical Output Characteristics,  $T_C = 25$  °C

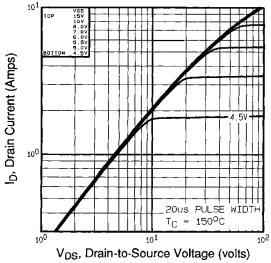


Fig. 2 - Typical Output Characteristics, T<sub>C</sub> = 150 °C

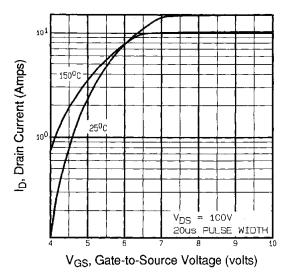


Fig. 3 - Typical Transfer Characteristics

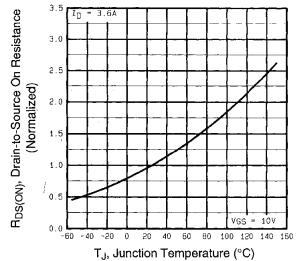


Fig. 4 - Normalized On-Resistance vs. Temperature



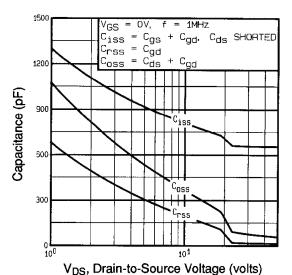


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

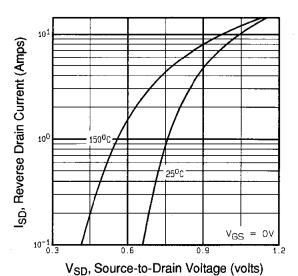


Fig. 7 - Typical Source-Drain Diode Forward Voltage

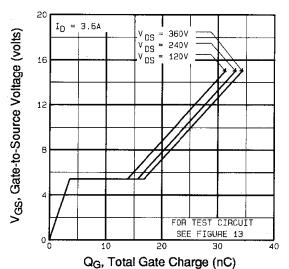


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

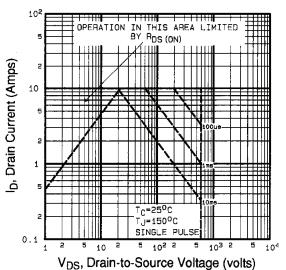


Fig. 8 - Maximum Safe Operating Area



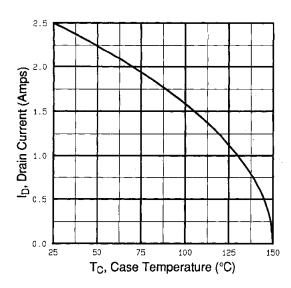


Fig. 9 - Maximum Drain Current vs. Case Temperature

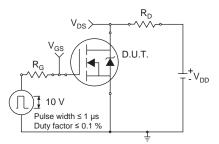


Fig. 10a - Switching Time Test Circuit

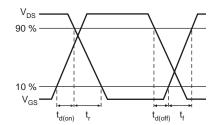


Fig. 10b - Switching Time Waveforms

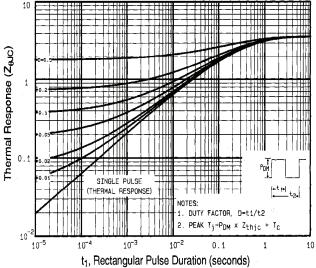


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

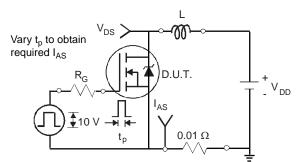


Fig. 12a - Unclamped Inductive Test Circuit

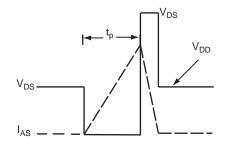


Fig. 12b - Unclamped Inductive Waveforms



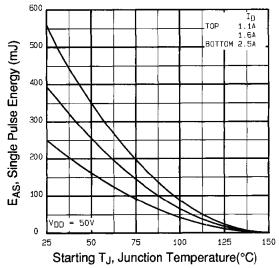


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

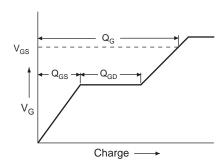


Fig. 13a - Basic Gate Charge Waveform

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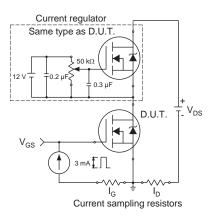
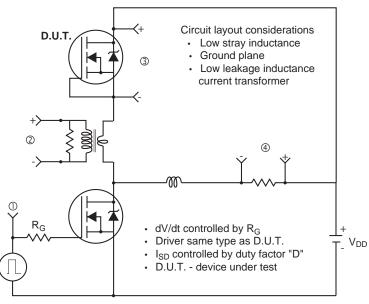


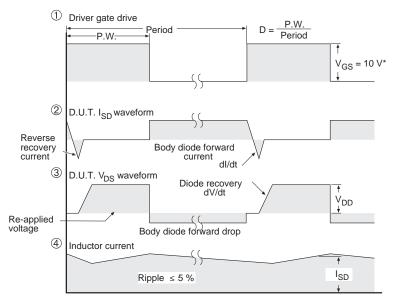
Fig. 13b - Gate Charge Test Circuit



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## Peak Diode Recovery dV/dt Test Circuit



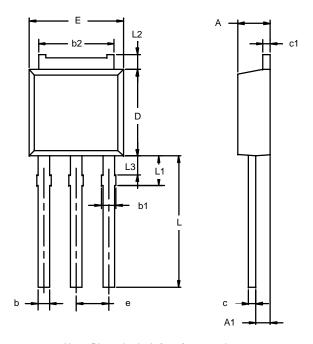


\* V<sub>GS</sub> = 5 V for logic level devices and 3 V drive devices

Fig. 14 - For N-Channel



### TO-251AA (DPAK)



Note: Dimension L3	is for reference only.
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	MILLIM	IETERS	INC	HES	
Dim	Min	Max	Min	Max	
Α	2.21	2.38	0.087	0.094	
A1	0.89	1.14	0.035	0.045	
b	0.71	0.89	0.028	0.035	
b1	0.76	1.14	0.030	0.045	
b2	5.23	5.43	0.206	0.214	
С	0.46	0.58	0.018	0.023	
с1	0.46	0.58	0.018	0.023	
D	5.97	6.22	0.235	0.245	
E	6.48	6.73	0.255	0.265	
е	2.28	BSC	0.090 BSC		
L	8.89	9.53	0.350	0.375	
L1	1.91	2.28	0.075	0.090	
L2	0.89	1.27	0.035	0.050	
L3	1.15	1.52	0.045	0.060	
ECN: S-03946—Rev. E, 09-Jul-01 DWG: 5346					



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